

Abstract of the Disclosure:

An integrated module contains a microcontroller and a code/data memory, it being possible for an access to the memory and an external data transfer terminal to be controlled
5 by the microcontroller during normal operation. Furthermore, the carrying out of a test sequence for the functional testing of the memory can be controlled by the microcontroller in a test operation. In a method for checking the functionality of the memory, a command sequence on the basis of which the
10 microcontroller controls the carrying out of the test sequence is read into the module externally before the beginning of the test operation. The command sequence is executed on the microcontroller and defect data are stored in a defect data memory under the control of the microcontroller. Therefore,
15 it is possible to carry out a self-test of the memory, but no additional BIST hardware has to be provided for this purpose.

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